FAIRCHILD

SEMICONDUCTOR®

November 2013

FQD4P40 — P-Channel QFET[®] MOSFET

FQD4P40

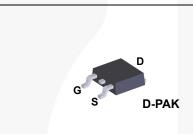
P-Channel QFET[®] MOSFET -400 V, -2.7 A, 3.1 Ω

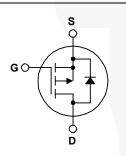
Description

These P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology. This advanced technology has been especially tailored to minimize onstate resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for electronic lamp ballast based on complimentary half bridge.

Features

- -2.7 A, -400 V, R_{DS(on)} = 3.1 Ω (Max.) @ V_{GS} = -10 V, I_D = -1.35 A
- Low Gate Charge (Typ. 18 nC)
- Low Crss (Typ. 11 pF)
- 100% Avalanche Tested





Absolute Maximum Ratings T_c = 25°C unless otherwise noted.

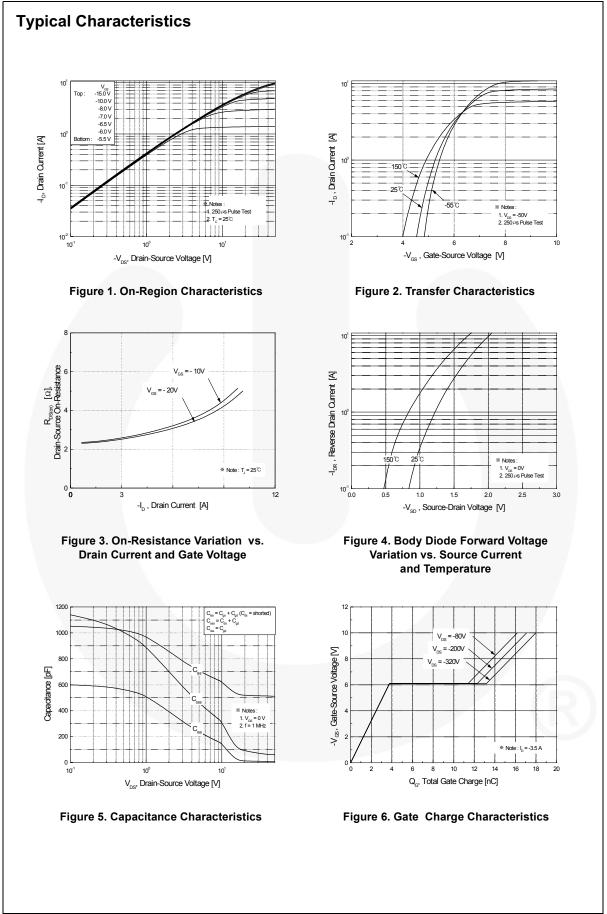
Symbol	Parameter		FQD4P40TM	Unit	
V _{DSS}	Drain-Source Voltage	-400	V		
ID	Drain Current - Continuous (T _C = 25°	C)	-2.7	А	
	- Continuous (T _C = 100	-1.71	A		
I _{DM}	Drain Current - Pulsed	(Note 1)	-10.8	A	
V _{GSS}	Gate-Source Voltage		± 30	V	
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	260	mJ	
I _{AR}	Avalanche Current	(Note 1) -2.7		A	
E _{AR}	Repetitive Avalanche Energy	(Note 1)	5.0	mJ	
dv/dt	Peak Diode Recovery dv/dt (Note 3)		-4.5	V/ns	
P _D	Power Dissipation ($T_A = 25^{\circ}C$) *	2.5			
	Power Dissipation ($T_C = 25^{\circ}C$)	50 V			
	- Derate above 25°C	0.4	W/°C		
T _J , T _{STG}	Operating and Storage Temperature Rar	-55 to +150	°C		
TL	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C	

Thermal Characteristics

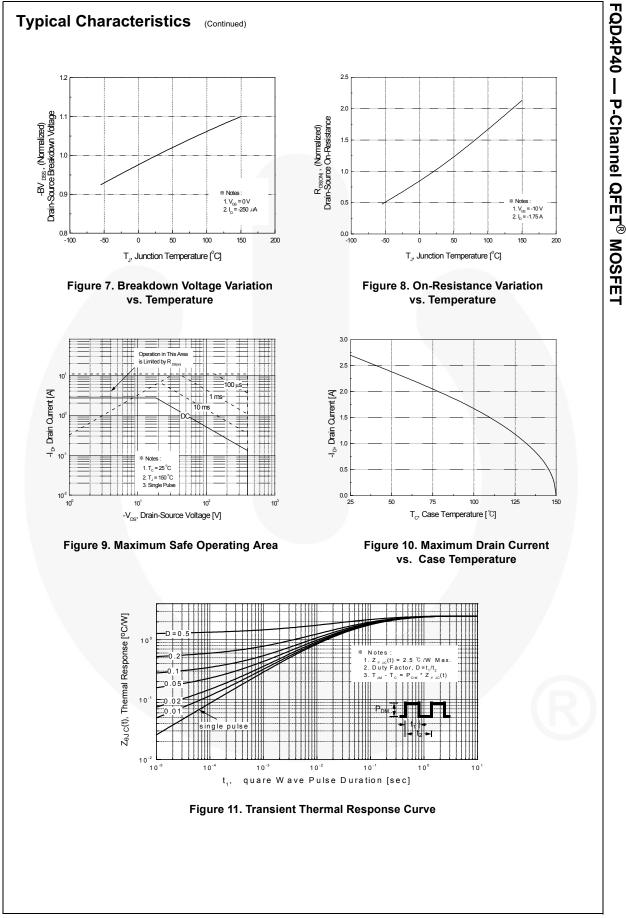
Symbol	Parameter	FQD4P40TM	Unit
R_{\thetaJC}	Thermal Resistance, Junction to Case, Max.	2.5	
P	Thermal Resistance, Junction to Ambient (Minimum Pad of 2-oz Copper), Max.	110	°C/W
R_{\thetaJA}	Thermal Resistance, Junction to Ambient (*1 in ² Pad of 2-oz Copper), Max.	50	

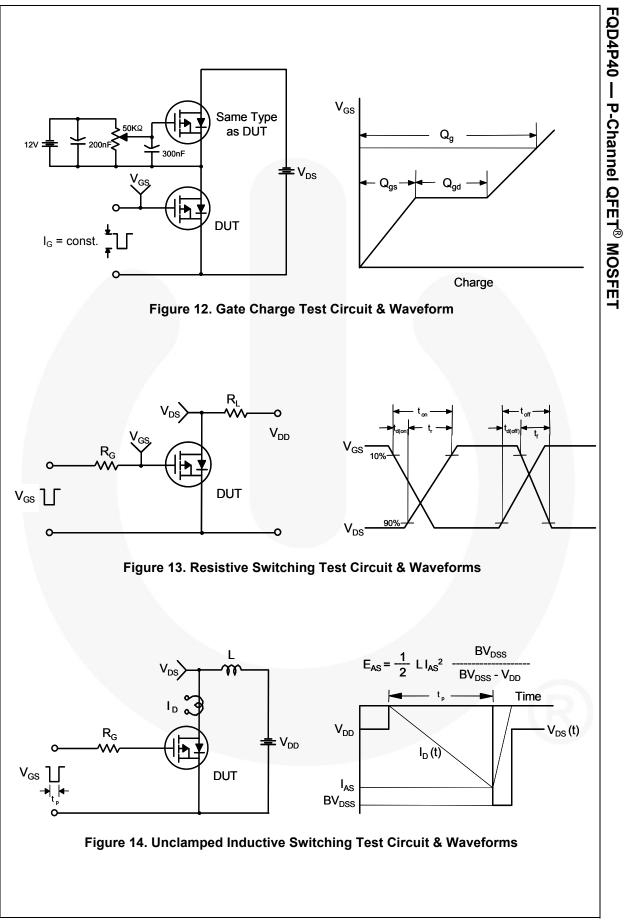
Part Number FQD4P40TM				kagePacking MethodReel \$PAKTape and Reel330 r		Size	Tape Width		Quantity		
						330 ı	nm	16 mm		2500 units	
ectri	cal Ch	aracteristics	Γ _c = 25°C un	less otherw	rise noted.						
Symbol		Parameter			Test Cor	ditions		Min	Тур	Мах	Unit
Off Cha	racteri	stics									
BV _{DSS}	Off Characteristics SV _{DSS} Drain-Source Breakdown Voltage		V _{GS} = 0 V, I _D = -250 μA				-400			V	
ΔBV _{DSS}	Breakdown Voltage Temperature										-
$/ \Delta T_J$				$I_D = -250 \ \mu A$, Referenced to 25°C				0.36		V/°C	
I _{DSS}	Zero Gate Voltage Drain Current		V_{DS} = -400 V, V_{GS} = 0 V					-1	μA		
			V _{DS} = -320 V, T _C = 125°C					-10	μA		
I _{GSSF}		ody Leakage Current,			-30 V, V _{DS}					-100	nA
I _{GSSR}	Gate-Bo	ody Leakage Current,	Reverse	V _{GS} =	30 V, V _{DS}	= 0 V				100	nA
On Cha	racteri	stics									
V _{GS(th)}		reshold Voltage	_	V _{DS} =	V _{GS} , I _D = -	250 μΑ		-3.0		-5.0	V
R _{DS(on)}	Static D On-Res	rain-Source istance		V _{GS} =	-10 V, I _D =	-1.35 A			2.44	3.1	Ω
9 _{FS}	Forward	d Transconductance	_	V _{DS} =	-50 V, I _D =	-1.35 A			2.5		S
Duran	o Char			1					+		
	1	acteristics	_	1		_			500	000	
C _{iss}	•	apacitance	_		-25 V, V _{GS}	= 0 V,			520	680	pF
C _{oss}		Capacitance		f = 1.0	MHz				80	105 15	pF
C _{rss}	Reveise	e Transfer Capacitanc	e						11	15	pF
Switchi	ng Cha	racteristics									
t _{d(on)}	Turn-Or	n Delay Time		Vpp =	-200 V, I _D	= -3 5 A			13	35	ns
t _r	Turn-Or	n Rise Time		$R_G = 2$	-	0.074,			55	120	ns
t _{d(off)}	Turn-Of	f Delay Time		0					35	80	ns
t _f	Turn-Of	f Fall Time				(Note 4)		37	85	ns
Qg	Total Ga	ate Charge		V _{DS} =	-320 V, I _D :	= -3.5 A,			18	23	nC
Q _{gs}	Gate-So	ource Charge		V _{GS} =	-10 V				3.8		nC
Q _{gd}	Gate-D	rain Charge				(Note 4)		9.4		nC
Drain-S	ourco	Diode Characteri	etice a	nd Max	vimum R	atings					
I _S	1	m Continuous Drain-S								-2.7	Α
I _{SM}		m Pulsed Drain-Source								-10.8	Α
V _{SD}		ource Diode Forward			0 V, I _S = -2	2.7 A				-5.0	V
t _{rr}		e Recovery Time	0		0 V, I _S = -3				260		ns
Q _{rr}		e Recovery Charge		00	t = 100 A/μ				1.4		μC
lotes:									1		
		-width limited by maximum ju , V_{DD} = -50 V, R_{G} = 25 Ω , star									

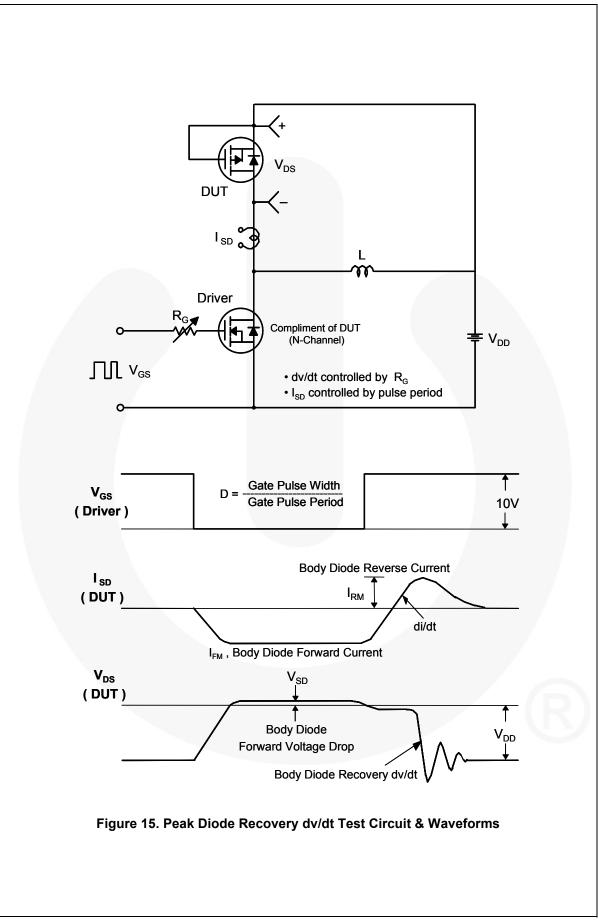
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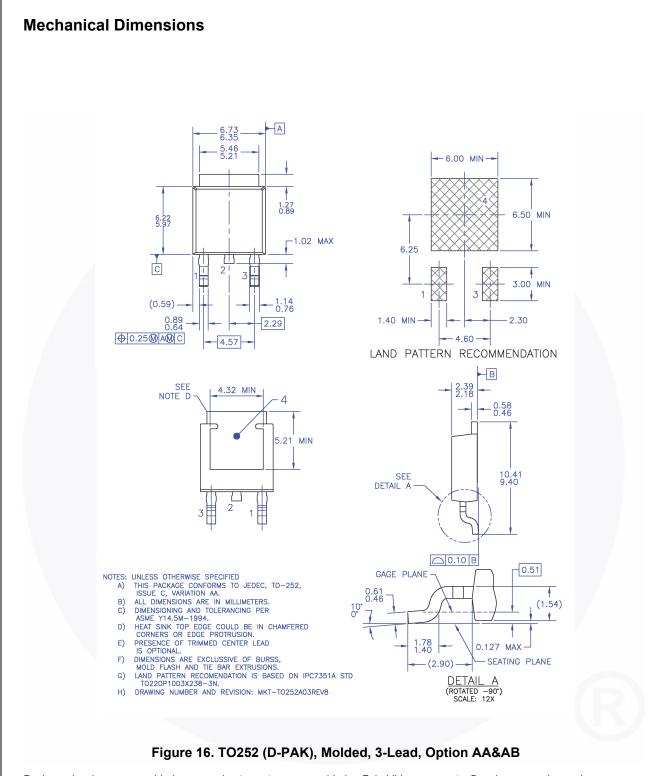


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notice to improve design.

First Production

Full Production

Preliminary

No Identification Needed

Rev. 166

Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without

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